

### General Description

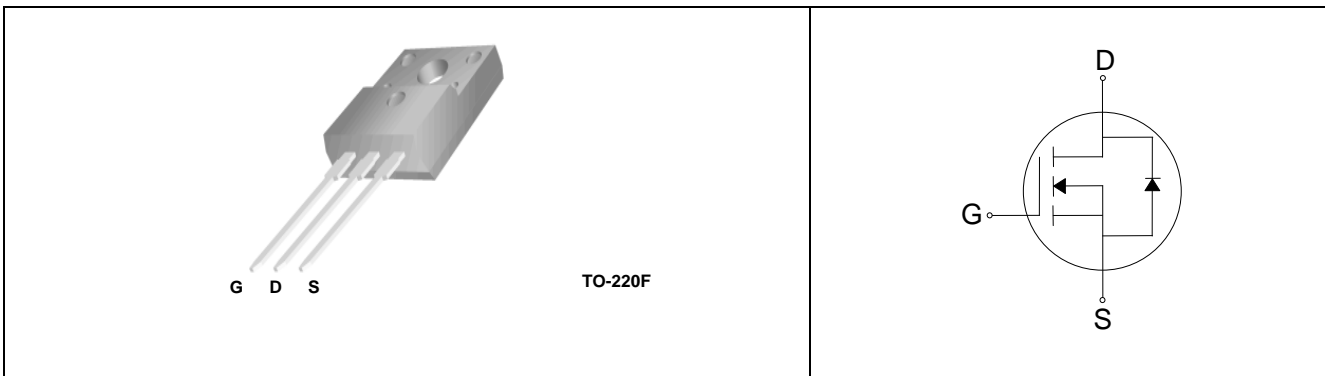
This Power MOSFET is produced using Maple semi's Advanced Super-Junction technology.

This advanced technology has been especially tailored to minimize conduction loss, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode.

These devices are well suited for AC/DC power conversion

### Features

- 22A, 600V, RDS(on) typ.= 150mΩ@VGS =10 V
- Low gate charge ( typical 42nC)
- High ruggedness
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability



### Absolute Maximum Ratings

TC = 25°C unless otherwise noted

Symbol	Parameter	SLF60R190SS	Units
VDSS	Drain-Source Voltage	600	V
ID	Drain Current	- Continuous (TC = 25°C)	22
		- Continuous (TC = 100°C)	10
IDM	Drain Current - Pulsed (Note 1)	66	A
VGSS	Gate-Source Voltage	±20	V
EAS	Single Pulsed Avalanche Energy (Note 2)	186	mJ
dv/dt	Peak Diode Recovery dv/dt (Note 3)	50	V/ns
PD	Power Dissipation (TC = 25°C)		38
		- Derate above 25°C □	0.3
TJ, TSTG	Operating and Storage Temperature Range	-55 to +150	°C
TL	Maximum lead temperature for soldering purposes,	300	°C
	1/8" from case for 5 seconds		

\*Drain current limited by maximum junction temperature.

### Thermal Characteristics

Symbol	Parameter	Value	Units
RθJC	Thermal Resistance, Junction-to-Case	3.3	°C/W
RθJA	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

**Electrical Characteristics** ( TC = 25 °C unless otherwise noted )

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
<b>Off Characteristics</b>						
BVDSS	Drain-Source Breakdown Voltage	VGS = 0V, ID = 250uA, TJ=25°C	600	-	-	V
		VGS = 0V, ID = 250uA, TJ=150°C	-	600	-	V
$\Delta$ BVDSS $\Delta$ TJ	Breakdown Voltage Temperature coefficient	ID = 250uA, referenced to 25°C	-	0.6	-	V/°C
IDSS	Drain-Source Leakage Current	VDS =600V, VGS = 0V	-	-	1	uA
		VDS =480V, TC = 125 °C	-	10	-	uA
IGSS	Gate-Source Leakage, Forward	VGS = 20V, VDS = 0V	-	-	100	nA
	Gate-source Leakage, Reverse	VGS = -20V, VDS = 0V	-	-	-100	nA

**On Characteristics**

VGS(th)	Gate Threshold Voltage	VDS = VGS, ID = 250uA	2.5	3.5	4.5	V
RDS(ON)	Static Drain-Source On-state Resistance	VGS =10 V, ID = 23.5A	-	0.15	0.19	$\Omega$

**Dynamic Characteristics**

Ciss	Input Capacitance	VGS =0 V, VDS =25V, f = 1MHz	-	1514	-	pF
Coss	Output Capacitance		-	60	-	
Crss	Reverse Transfer Capacitance		-	36	-	

**Dynamic Characteristics**

td(on)	Turn-on Delay Time	VDD =300V, ID =25A, RG =25 $\Omega$	-	19.1	-	nS
tr	Rise Time		-	56.7	-	
td(off)	Turn-off Delay Time		-	61.1	-	
tf	Fall Time		-	41.8	-	
Qg	Total Gate Charge	VDS =480V, VGS =10V, ID =25A	-	42.3	-	nC
Qgs	Gate-Source Charge		-	10.1	-	
Qgd	Gate-Drain Charge(Miller Charge)		-	19.4	-	

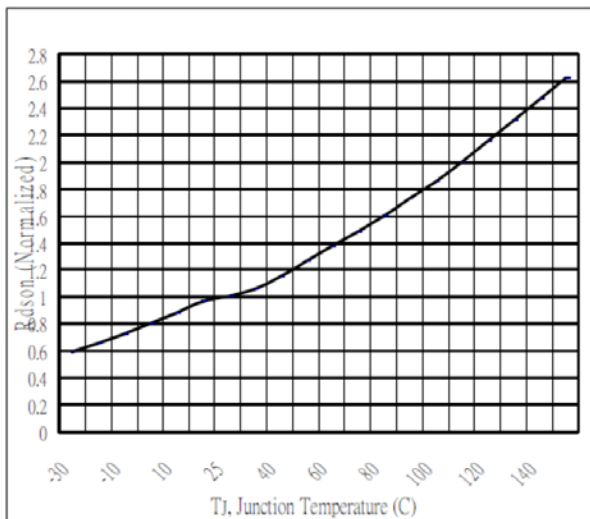
**Source-Drain Diode Ratings and Characteristics**

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit.
IS	Maximum Continuous Drain-Source Diode Forward Current		-	-	23	A
ISM	Maximum Pulsed Drain-Source Diode Forward Current		-	-	66	
VSD	Diode Forward Voltage	IS =25A, VGS =0V	-	-	1.5	V
trr	Reverse Recovery Time	IS =25A, VGS=0V, dIF/dt=100A/us	-	399	-	nS
Qrr	Reverse Recovery Charge		-	1.4	-	uC

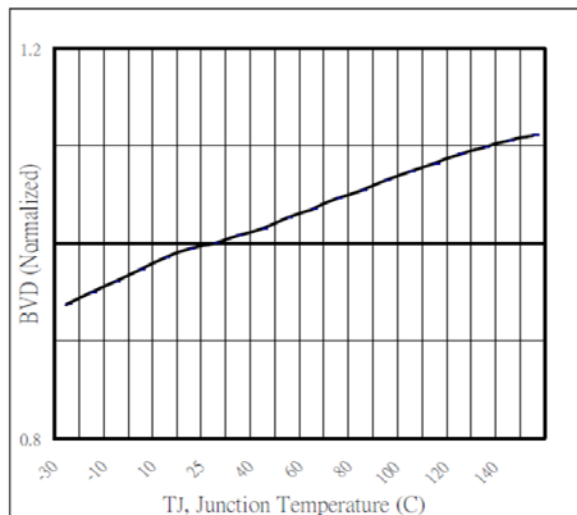
**NOTES**

1. Repeatability rating : pulse width limited by junction temperature
2. L =10mH, IAS =6.1A, VDD = 50V, RG = 25 $\Omega$ , Starting TJ = 25°C
3. ISD  $\leq$  ID, di/dt  $\leq$  200A/us, VDD  $\leq$  BVDSS, Starting TJ = 25°C
4. Pulse Test : Pulse Width  $\leq$  300us, Duty Cycle  $\leq$  2%
5. Essentially independent of operating temperature.

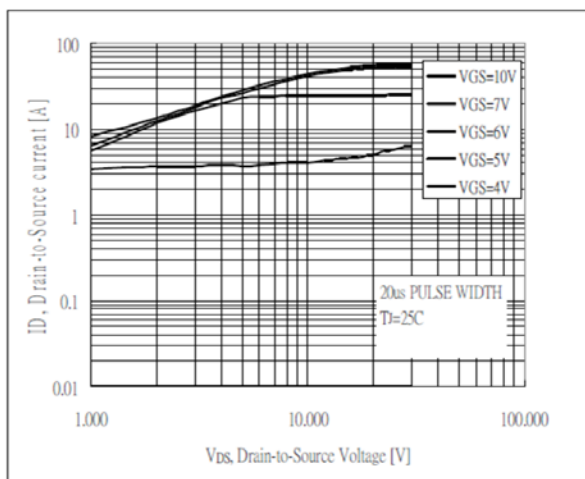
# TYPICAL ELECTRICAL CHARACTERISTICS



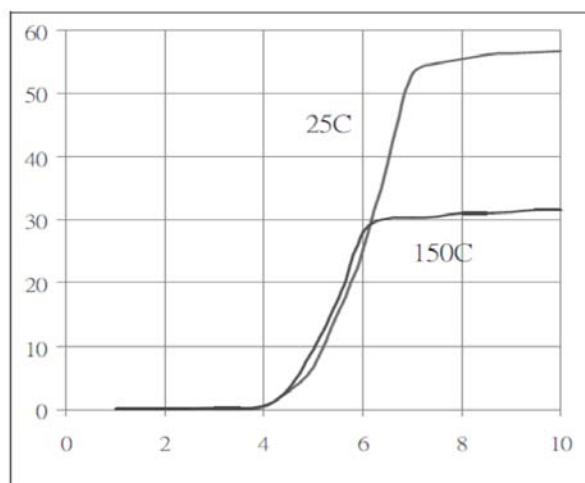
**Fig 1. On-Resistance Variation with vs. Temperature**



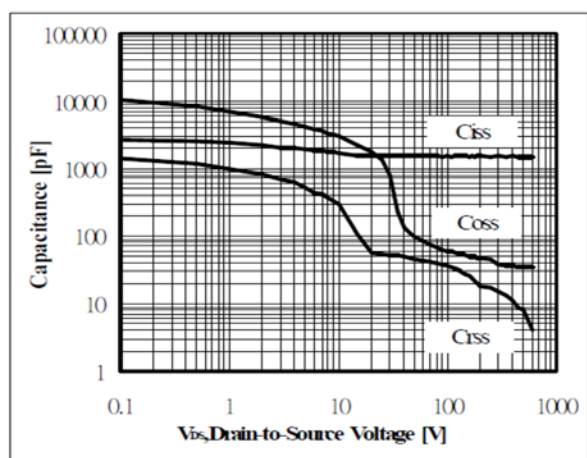
**Fig.2 Breakdown Voltage Variation vs. Temperature**



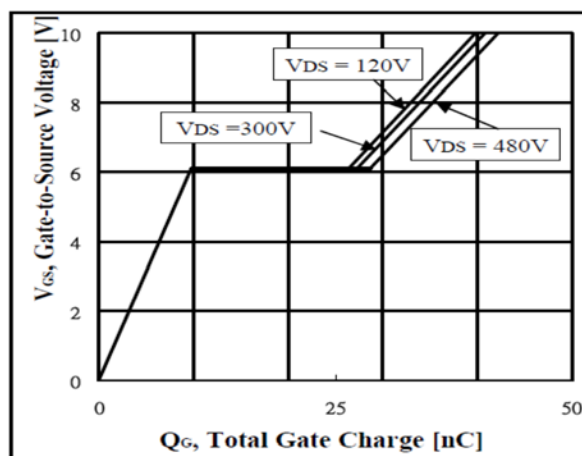
**Fig 3. Typical Output Characteristics**



**Fig 4. Typical Transfer Characteristics**

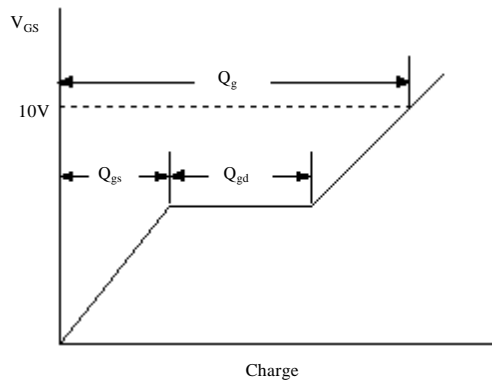
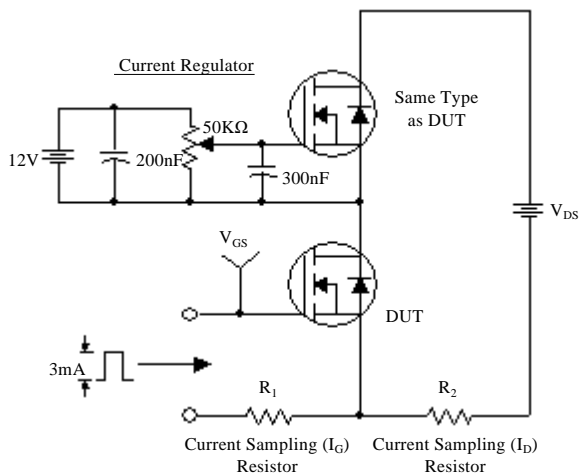


**Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage**

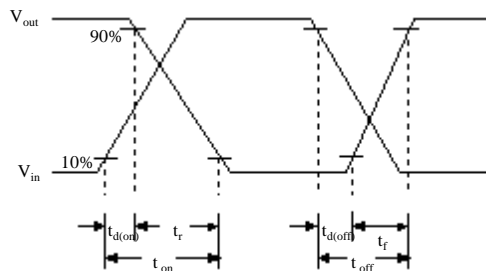
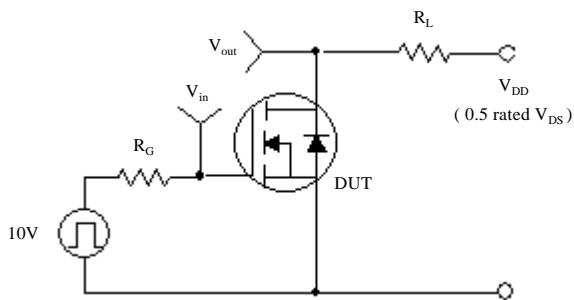


**Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage**

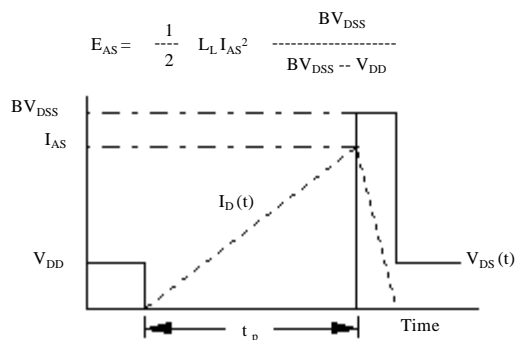
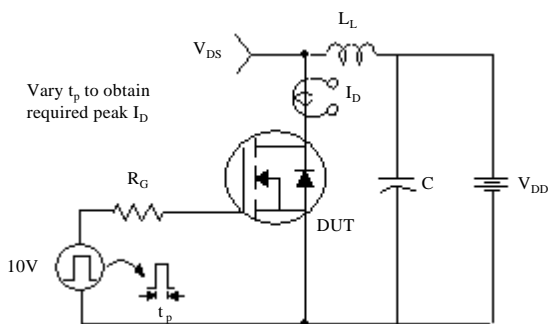
### Gate Charge Test Circuit & Waveform



### Resistive Switching Test Circuit & Waveforms



### Unclamped Inductive Switching Test Circuit & Waveforms



### Peak Diode Recovery dv/dt Test Circuit & Waveforms

